

عنوان مقاله:

Characterization and Passive Spectrometry of Pulsed X-ray Emission From Δ kJ Plasma Focus Device

محل انتشار:

هفتمین کنفرانس بین المللی فیزیک، ریاضی و توسعه علوم پایه (سال: 1402)

تعداد صفحات اصل مقاله: 9

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خلاصه مقاله:

The results of the investigation of the radiation emission X-ray from a Δ kJ Mather Type Plasma Focus (MTPF) operated in argon are presented. The charging voltage was 12 kV and the operating pressure was in the range of 0.2–0.7 torr. Several diagnostics techniques such as Rogowski coil, five-channel PIN diode and scintillator-photomultiplier were employed during the project. The signals obtained from the detectors were analyzed using MATLAB software. The pressure 0.3 torr of argon was found to give maximum X-ray yield. In the following, the passive spectroscopy method, using radiographic film with Al attenuation filters, was used to determine the spectrum of pulsed X-ray emitted from the MTPF. In order to determine the spectrum according to the recorded doses, solving linear equations was used. The results showed when the MTPF device is operated by working voltage of 12 kV and 0.3 torr argon gas injection, the X-ray spectrum extends from 10 keV to 250 keV with a maximum of 120 keV. A reliable low-energy plasma focus device with X-ray emission could be used as an X-ray source in various technological fields

کلمات کلیدی:

Plasma Focus Device, X-ray - passive spectroscopy method

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<https://civilica.com/doc/1762151>



